

LARGE-SCALE GROWTH AND PROPERTIES OF LAMELLAR VANADIUM SULPHIDE

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CONTEXTE OF THE WORK

Anode

Weight Percent Vanadium

- VS₂ has been reported with a 2D-layered structure \bullet
- VS₂ is known to show specific conduction mechanisms and simulation predicts a semi-metallic behavior.
- It is highly conductive along the 2D plans.

It is difficult to stabilize due to the high solubility of sulfur in the V-S structure



It is highly reactive with oxygen in ambient atmosphere.

Synthesis has been achieved on small surfaces using de-lithiatium process of LiVS₂ or in the form of flakes in CVD mode^{1,2}

Is there any solution to grow and stabilize VS₂ on large surface ?

EXPERIMENTAL SECTION

- The deposition is based on a 2 steps process : <u>deposition of amorphous</u> <u>VS₂ by ALD/CVD at low temperature followed by annealing.</u>
- The growth is achieved in an ALD/CVD reactor at 200°C, using TEMAV and ethane di-thiol as chemical precursors.
- Annealing is achieved at medium temperature in a controlled environment to insure crystallization.



GROWTH RESULTS

<u>A stable growth condition is obtained at</u> 200°C at rate of 1Å per ALD/CVD cycle.



VOx

 $V_x C_y S_z$

 SiO_2

Polysulfides, oxygen and carbon are alloyed in the film resulting on a stoichiometry of $VS_{1,1}O$ (C~5%).



The <u>oxygen is mainly localized on top of an amorphous V_xC_yS₂ layer</u>

2.10 nm



ANNEALING AND ELECTRICAL PROPERTIES

Amorphous film deposited on 300mm Borosilicate wafer shows a resistivity <1mOhm.cm.



After etching using Kapton masking, ithe conductivity s preserved



The as-deposited film is relatively transparent <u>@7nm with a 70% of photons</u> transmission recorded in the range 500 - 3000 cm⁻¹ on Borosilicate substrate



After annealing, the film crystallizes in a 2D lamellar structure.

Z-contrast TEM image



After annealing, the hall measurement in temperature indicates that the conductivity is due to p-type carriers.



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